## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Group Art Unit: To Be Assigned

Examiner: To Be Assigned

In Re PATENT APPLICATION Of:

**Applicants** Ryoichi AOYAMA et al. Serial No. To Be Assigned **INFORMATION** Filed December 31, 2003 **DISCLOSURE STATEMENT** For SELF-CLEANING METHOD FOR SEMICONDUCTOR EXPOSURE **APPARATUS** 

Attorney Ref.: OKI 395 December 31, 2003

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

This is an information disclosure statement submitted in compliance with the timing requirements of 37 C.F.R. §1.97(b)(1).

Attached are copies of three Japanese patent publications. Any relevance of the Japanese patent publications can be gleaned from the attached English-language Abstracts. The patent publications are listed on the attached Form PTO-1449. Also listed on the Form PTO-1449 for consideration are two U.S. patents. Any relevance of these U.S. patents is self-evident.

Since this Information Disclosure Statement is being filed with the application, no certification or fee is required, and the requirements of 37 C.F.R. §§1.97 and 1.98 are deemed to be fully met as to the documents submitted. Consideration of the submitted and listed documents is respectfully requested.

Respectfully submitted,

December 31, 2003

Date

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FORM PTO-1449 INFORMATION DISCLOSURE STATEMENT				Atty Docket	Applica	Application No.		
				OKI 395	To Be	To Be Assigned		
				Applicant  Ryoichi AOYAMA et al.				
				Filing Date	Group	Group Unit		
				December 31, 2003	To Be	To Be Assigned		
			U.S.	PATENT DOCUMENTS	<u>I</u>			
Examiner Initial		Document Number	Date	Name	Class	Sub- Class	Filing Date	
	AA	6,268,904	07/31/01	Mori et al.				
	AB	5,981,960	11/09/99	Ooaeh et al.				
	AC							
	AD							
	AE	:	<u> </u>					
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	AH							
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	AJ						<u></u>	
	<del></del>	,	FOREI	GN PATENT DOCUMENTS			·	
		Document Number	Date	Country	Class	Sub- Class	Trans- lation	
	AK	2002-246296	08/30/02	Japan			Abstract	
·-	AL	11-224839	08/17/99	Japan			Abstract	
	AM	05-335206	12/17/93	Japan			Abstract	
	AN							
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Examiner				Date Consid	dered			
EXAMINER citation if not	: Initial	if reference cons	idered, wheth	er or not citation is in conformance v nclude copy of this form with next co	with MPEP 609;	draw line Applicar	through nt.	